PATENT ABSTRACTS OF JAPAN

(11)Publication number:

57-113243

(43)Date of publication of application: 14.07.1982

(51)Int.Cl.

H01L 21/66

(21)Application number : 55-189220

(71)Applicant: HASEGAWA YOSHIE

(22)Date of filing:

29.12.1980

(72)Inventor: HASEGAWA YOSHIE

(54) STATIONARY PROBE BOARD

(57)Abstract:

PURPOSE: To improve the reliability of test result by securing a stationary end to a mounting piece with conductivity, extending approximately axially of the mounting piece the end, and bending to face with the measuring electrode, thereby preventing the piezo effect. CONSTITUTION: Many probe needles 2' are radially arranged at the ends to be positioned at the electrodes of semiconductor chips to be measured at the position of a rectangular hole 9 formed at the center of a printed board 1. The other end of the mounting piece 10 of the needle is electrically connected via solder to the connecting end of the wiring pattern 6 of the substrate 1. The printed board 1 and the probe needle are integrally secured by the ringshaped stationary unit 11 formed of insulating securing material so that the surface of the mounting piece becomes vertical to the mounting surface of the substrate 1.

